Errata AM263x Sitara MCU Silicon Revision 1.0A



ABSTRACT

This document describes the known exceptions to the functional specifications (advisories). This document may also contain usage notes. Usage notes describe situations where the device's behavior may not match presumed or documented behavior. This may include behaviors that affect device performance or functional correctness.

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1 Usage Notes and Advisories Matrices

Table 1-1 lists all usage notes and the applicable silicon revision(s). Table 1-2 lists all advisories, modules affected, and the applicable silicon revision(s).

Table 1-1. Usage Notes Matrix

Module	DESCRIPTION	SILICON REVISIONS AFFECTED AM263x
		1.0A
CLOCKS	i2324 — No synchronizer present between GCM and GCD status signals	YES
VDDA	i2348 — VDDA1V8 Static Power leakage	YES

Table 1-2. Advisories Matrix

	DESCRIPTION	SILICON REVISIONS AFFECTED AM263x	
MODULE			
		1.0A	
ADC	i2346 — ADC result has Error when switching between odd and even channels	YES	
ADC	i2347 — VREF current consumption of ADC is random at powerup	YES	
ADC	i2349 — ADC VrefHi Loading increase in powerdown	YES	
CONTROLSS	i2352 — CONTROLSS-SDFM: Dynamically Changing Threshold Settings (LLT, HLT), Filter Type, or COSR Settings Will Trigger Spurious Comparator Events	YES	
CONTROLSS	i2353 — CONTROLSS-SDFM: Dynamically Changing Data Filter Settings (Such as Filter Type or DOSR) Will Trigger Spurious Data Acknowledge Events	YES	
CONTROLSS	i2354 — CONTROLSS-SDFM: Two Back-to-Back Writes to SDCPARMx Register Bit Fields CEVT1SEL, CEVT2SEL, and HZEN Within Three SD-Modulator Clock Cycles can Corrupt SDFM State Machine, Resulting in Spurious Comparator Events	YES	
CONTROLSS	i2355 — CONTROLSS-ADC: DMA Read of Stale Result	YES	
CONTROLSS	i2356 — CONTROLSS-ADC: Interrupts may Stop if INTxCONT (Continue-to-Interrupt Mode) is not Set	YES	
CONTROLSS	i2357 — CONTROLSS-ePWM: An ePWM Glitch can Occur if a Trip Remains Active at the End of the Blanking Window	YES	
CONTROLSS	i2358 — CONTROLSS-ePWM: Trip Events Will Not be Filtered by the Blanking Window for the First 3 Cycles After the Start of a Blanking	YES	
CONTROLSS	i2359 — CONTROLSS-CMPSS:Prescaler counter behaviour different from spec when DACSOURCE is made 0 or reconfigured as 1	YES	
CPSW	i2345 — CPSW: Ethernet Packet corruption occurs if CPDMA fetches a packet which spans across memory banks	YES	
GPMC	i2313 — GPMC: Sub-32-bit read issue with NAND and FPGA/FIFO	YES	
McSPI	i2350 — McSPI data transfer using EDMA in 'ABSYNC' mode stops after 32 bits transfer	YES	
MDIO	i2329 — MDIO interface corruption (CPSW and PRU-ICSS)	YES	
UART	i2310 — USART: Erroneous triggering of timeout interrupt	YES	
UART	i2311 — UASRT: Spurious DMA Interrupts	YES	



2 Silicon Usage Notes

i2324 No synchronizer present between GCM and GCD status signals

Details: There is no synchronizer in between GCM and GCD, so the clock configuration register

reads may be incorrect momentarily.

Severity: Minor

Workaround(s): Poll for the status registers change until it reflects the programmed SRC SEL and DIV

values.

i2348 VDDA1V8 Static Power leakage

Details: VDDA1V8 has static leakage when the device is booted if DACVREF is at ground.

Workaround(s): DAC reference voltage and VDDA1p8V must be shorted together.

3 Silicon Advisories

i2310 USART: Erroneous clear/trigger of timeout interrupt

Details: The USART may erroneously clear or trigger the timeout interrupt when RHR/MSR/LSR

registers are read.

Workaround(s):

For CPU use-case.

If the timeout interrupt is erroneously cleared:

-This is OK since the pending data inside the FIFO will retrigger the timeout interrupt

If timeout interrupt is erroneously set, and the FIFO is empty, use the following SW

workaround to clear the interrupt:

- Set a high value of timeout counter in TIMEOUTH and TIMEOUTL registers

- Set EFR2 bit 6 to 1 to change timeout mode to periodic
- Read the IIR register to clear the interrupt
- Set EFR2 bit 6 back to 0 to change timeout mode back to the original mode

For DMA use-case.

If timeout interrupt is erroneously cleared:

- -This is OK since the next periodic event will retrigger the timeout interrupt
- -User must ensure that RX timeout behavior is in periodic mode by setting EFR2 bit6 to 1

If timeout interrupt is erroneously set:

- -This will cause DMA to be torn down by the SW driver
- -OK since next incoming data will cause SW to setup DMA again

i2311 USART Spurious DMA Interrupts

Details: Spurious DMA interrupts may occur when DMA is used to access TX/RX FIFO with a

non-power-of-2 trigger level in the TLR register.

Workaround(s):



i2311 (continued) USART Spurious DMA Interrupts

Use power of 2 values for TX/RX FIFO trigger levels (1, 2, 4, 8, 16, and 32).

i2313 GPMC: Sub-32-bit read issue with NAND and FPGA/FIFO

Details: Sub-32-bit reads on the GPMC interface will miss portions of the data, which will result in incorrect read data. This includes 8-bit or 16-bit reads from a NAND device or from

an FPGA or FIFO interface. Note that 3-byte accesses are not allowed on the GPMC

interface.

Workaround(s):

Details:

Read accesses on the GPMC interface must be performed as 32-bit reads. Writes are not

affected by this erratum.

i2329 MDIO: MDIO interface corruption (CPSW and PRU-ICSS)

It is possible that the MDIO interface of all instances of CPSW and PRU-ICSS peripherals (if present) returns corrupt read data on MDIO reads (e.g. returning stale or previous data), or sends incorrect data on MDIO writes. It is also possible that the MDIO interface becomes unavailable until the next peripheral reset (either by LPSC reset or global device reset with reset isolation disabled in case of CPSW).

Possible system level manifestations of this issue could be (1) erroneous ethernet PHY link down status (2) inability to properly configure an ethernet PHY over MDIO (3) incorrect PHY detection (e.g. wrong address) (4) read or write timeouts when attempting to configure PHY over MDIO.

For boot mode (only CPSW if supported), there is no workaround to guarantee the primary ethernet boot is successful. If this exception occurs during primary boot, the boot may possibly initiate retries which may or may not be successful. If the retries are unsuccessful, this would result in an eventual timeout and transition to the backup boot mode (if one is selected). If no backup boot mode is selected, then such failure will result in a timeout and force device reset via chip watchdog after which the complete boot process will restart again.

To select a backup boot option (if supported), populate the appropriate pull resistors on the boot mode pins. See boot documentation for each specific device options, but the typical timeout for primary boot attempts over ethernet is 60 seconds.

Workaround(s): On affected devices, following workaround should be used:

MDIO manual mode: applicable for PRU-ICSS and for CPSW.

MDIO protocol can be emulated by reading and writing to the appropriate bits within the MDIO_MANUAL_IF_REG register of the MDIO peripheral to directly manipulate the MDIO clock and data pins. Refer to TRM for full details of manual mode register bits and their function.

In this case the device pin multiplexing should be configured to allow the IO to be controlled by the CPSW or PRU-ICSS peripherals (same as in normal intended operation), but the MDIO state machine must be disabled by ensuring MDIO_CONTROL_REG.ENABLE bit is 0 in the MDIO_CONTROL_REG and enable manual mode by setting MDIO_POLL_REG.MANUALMODE bit to 1.

Contact TI regarding implementation of software workaround.



i2329 (continued)

MDIO: MDIO interface corruption (CPSW and PRU-ICSS)

Note

If using Ethernet DLR (Device Level Ring) (on CPSW or PRU-ICSS) or EtherCat protocol (on PRU-ICSS) there may be significant CPU or PRU loading impact to implement the run-time workaround 1 due to required polling interval for link status checks. Resulting system impact should be considered.

In case of PRU-ICSS, the loading of the software workaround may be reduced by using the MLINK feature of MDIO to do automatic polling of link status via the MIIx_RXLINK input pin to PRU-ICSS which must be connected to a status output from the external PHY which does not toggle while the link is active. Depending on the specified behavior of the external PHY device, this PHY status output may be LED_LINK or LED_SPEED or the logic OR of LED_LINK and LED SPEED. Refer to the MDIO section of TRM for details on using the MLINK feature of MDIO. This feature is not available on the CPSW peripheral.

For EtherCAT implementation on PRU-ICSS, the software workaround will be done in RTUx/ TX_PRUx Core. The core will have to be dedicated for workaround, which means this can't be used for other purpose. The implementation will support two user access channels for MDIO access. This provides option for R5f core and PRU core to have independent access channel. The APIs will be similar to the ones we will have in RTOS Workaround implementation.

EtherCAT will continue to use PHY fast link detection via MDIO MLINK bypassing state m/c for link status (as this path is not affected by errata). This makes sure that cable redundancy related latency requirements are still met.



i2329 (continued) MDIO: MDIO interface corruption (CPSW and PRU-ICSS)

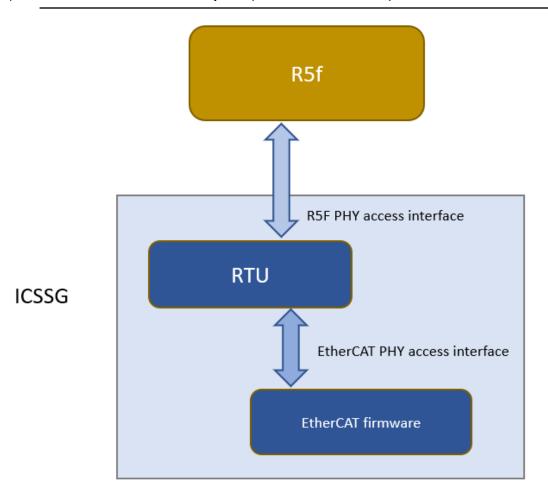


Figure 3-1. MDIO Emulation via Manual Mode using PRU Core

i2345 CPSW: Ethernet Packet corruption occurs if CPDMA fetches a packet which spans

across memory banks

Details: Each memory bank in SoC has a separate memory controller. Even though memory

addresses are contiguous, each bank is a separate entity with a separate controller.

If a memory bank received a memory request say 32 bytes and address of memory request is 16 bytes before end of memory bank, the behavior of the memory controller will

be:

When the memory controller encounters end of memory bank after 16 bytes it will wrap

around and give 16 bytes from the start of the memory bank.

This results in the packet corruption.

Workaround(s): Ensure from application side single ethernet packet does not span across memory banks.

i2346 ADC result has Error when switching between odd and even channels

Details: When a ADC conversion sequence involves sampling Odd and Even channels, there is

a error in the conversion result whenever there is a switch from odd channel to even

channel and vice versa.



Silicon Advisories

i2346 (continued) ADC result has Error when switching between odd and even channels

No error seen when the conversion involves switching between even channels only or odd

channels only.

The first sample after odd to even or even to odd channel switch must have smallest Workaround(s):

acquisition window and that result must be ignored.

i2347 VREF current consumption of ADC is random at powerup

Details: VREF current consumption is high after PORZ and goes low after enabling the ADC via

MMR.

The initial current consumption is random at each PORZ cycle.

Workaround(s): Never disable the ADC without resetting the DTC.

i2349 ADC VrefHi Loading increase in powerdown

Details: If ADC is disabled after conversion, the loading on reference increases by 2 mA.

Workaround(s): Never disable the ADC without resetting the DTC.

i2350 McSPI: McSPI data transfer using EDMA in 'ABSYNC' mode stops after 32 bits

transfer

Details: When EDMA is programmed to transfer more than 32 bits of data in to McSPI Tx FIFO

(32 Bytes), it stops working after transferring only first 32 bits data in to the FIFO.

This issue is observed only in "ABSYNC" mode of EDMA where the EDMA is configured

such that transfer size is more than 32 bits.

When the issue happens the EDMA neither transferring the data and completing it nor raising any error as vbusp sdone signal is not getting generated by McSPI for transaction

from EDMA.

SPI RX mode is not affected this issue.

Workaround(s): Option1: Use ASYNC mode of EDMA for McSPI TX operation

Option2: Use acnt=4, bcnt=1, ccnt=1 if ABSYNC mode is used for McSPI TX operation

i2352 CONTROLSS-SDFM: Dynamically Changing Threshold Settings (LLT, HLT), Filter

Type, or COSR Settings Will Trigger Spurious Comparator Events

Details: When SDFM comparator settings—such as filter type, lower/upper threshold, or

> comparator OSR (COSR) settings—are dynamically changed during run time, spurious comparator events will be triggered. The spurious comparator event will trigger a corresponding CPU interrupt, CLA task, ePWM X-BAR events, and GPIO output X-BAR

events if configured appropriately.

When comparator settings need to be changed dynamically, follow the procedure below Workaround(s):

to ensure spurious comparator events do not generate a CPU interrupt, CLA event, or

X-BAR events (ePWM X-BAR/GPIO output X-BAR events):

1. Disable the comparator filter.

2. Delay for at least a latency of the comparator filter + 3 SD-Cx clock cycles.

3. Change comparator filter settings such as filter type, COSR, or lower/upper threshold.

4. Delay for at least a latency of the comparator filter + 5 SD-Cx clock cycles.

5. Enable the comparator filter.



i2353

CONTROLSS-SDFM: Dynamically Changing Data Filter Settings (Such as Filter Type or DOSR) Will Trigger Spurious Data Acknowledge Events

Details:

When SDFM data settings—such as filter type or DOSR settings—are dynamically changed during run time, spurious data-filter-ready events will be triggered. The spurious data-ready event will trigger a corresponding CPU interrupt, CLA task, and DMA trigger if configured appropriately.

Workaround(s):

When SDFM data filter settings need to be changed dynamically, follow the procedure below to ensure spurious data-filter-ready events are not generated:

- 1. Disable the data filter.
- 2. Delay for at least a latency of the data filter + 3 SD-Cx clock cycles.
- 3. Change data filter settings such as filter type and DOSR.
- 4. Delay for at least a latency of the data filter + 5 SD-Cx clock cycles.
- Enable the data filter.

i2354

CONTROLSS-SDFM: Two Back-to-Back Writes to SDCPARMx Register Bit Fields CEVT1SEL, CEVT2SEL, and HZEN Within Three SD-Modulator Clock Cycles can Corrupt SDFM State Machine, Resulting in Spurious Comparator Events

Details:

Back-to-back writes to SDCPARMx register bit fields CEVT1SEL, CEVT2SEL, and HZEN within three SD-modulator clock cycles can potentially corrupt the SDFM state machine, resulting in spurious comparator events, which can potentially trigger CPU interrupts, CLA tasks, ePWM XBAR events, and GPIO output X-BAR events if configured appropriately.

Workaround(s):

Avoid back-to-back writes within three SD-modulator clock cycles or have the SDCPARMx register bit fields configured in one register write.

i2355

CONTROLSS-ADC: DMA Read of Stale Result

Details:

The ADCINT flag can be set before the ADCRESULT value is latched (see the tLAT and tINT(LATE) columns in the ADC Timings tables of the AM263x Technical Reference Manual).

The DMA can read the ADCRESULT value as soon as 3 cycles after the ADCINT trigger is set. As a result, the DMA could read a prior ADCRESULT value when the user expects the latest result if all of the following are true:

- The ADC is in late interrupt mode.
- The ADC operates in a mode where tINT (LATE) occurs 3 or more cycles before tLAT (ADCCTL2 [PRESCALE] > 2 for 12-bit mode).
- The DMA is triggered from the ADCINT signal.
- The DMA immediately reads the ADCRESULT value associated with that ADCINT signal without reading any other values first.
- The DMA was idle when it received the ADCINT trigger.

Only the DMA reads listed above could result in reads of stale data; the following non-DMA methods will always read the expected data:

- The ADCINT flag triggers a CLA task.
- The ADCINT flag triggers a CPU ISR.
- · The CPU polls the ADCINT flag.

Workaround(s):

Trigger two DMA channels from the ADCINT flag. The first channel acts as a dummy transaction. This will result in enough delay that the second channel will always read the fresh ADC result.



i2356

CONTROLSS-ADC: Interrupts may Stop if INTxCONT (Continue-to-Interrupt Mode) is not Set

Details:

If ADCINTSELxNx[INTxCONT] = 0, then interrupts will stop when the ADCINTFLG is set and no additional ADC interrupts will occur. When an ADC interrupt occurs simultaneously with a software write of the ADCINTFLGCLR register, the ADCINTFLG will unexpectedly remain set, blocking future ADC interrupts.

Workaround(s):

1. Use Continue-to-Interrupt Mode to prevent the ADCINTFLG from blocking additional ADC interrupts:

ADCINTSEL1N2[INT1CONT] = 1; ADCINTSEL1N2[INT2CONT] = 1; ADCINTSEL3N4[INT3CONT] = 1; ADCINTSEL3N4[INT4CONT] = 1;

- 2. Ensure there is always sufficient time to service the ADC ISR and clear the ADCINTFLG before the next ADC interrupt occurs to avoid this condition.
- Check for an overflow condition in the ISR when clearing the ADCINTFLG.
 Check ADCINTOVF immediately after writing to ADCINTFLGCLR; if it is set, then write ADCINTFLGCLR a second time to ensure the ADCINTFLG is cleared. The ADCINTOVF register will be set, indicating an ADC conversion interrupt was lost.

AdcaRegs.ADCINTFLGCLR.bit.ADCINT1 = 1; //clear INT1 flag if(1 == AdcaRegs.ADCINTOVF.bit.ADCINT1) //ADCINT overflow {

AdcaRegs.ADCINTFLGCLR.bit.ADCINT1 = 1; //clear INT1 again

// If the ADCINTOVF condition will be ignored by the application

// then clear the flag here by writing 1 to ADCINTOVFCLR.

// If there is a ADCINTOVF handling routine, then either insert

// that code and clear the ADCINTOVF flag here or do not clear

// the ADCINTOVF here so the external routine will detect the $\,$

// condition.

// AdcaRegs.ADCINTOVFCLR.bit.ADCINT1 = 1; // clear OVF

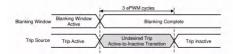
i2357

CONTROLSS-ePWM: An ePWM Glitch can Occur if a Trip Remains Active at the End of the Blanking Window

Details:

The blanking window is typically used to mask any PWM trip events during transitions which would be false trips to the system. If an ePWM trip event remains active for less than three ePWM clocks after the end of the blanking window cycles, there can be an undesired glitch at the ePWM output.

The following picture illustrates the time period which could result in an undesired ePWM output.



The following picture illustrates the two potential ePWM outputs possible if the trip event ends within 1 cycle before or 3 cycles after the blanking window closes.



i2357 (continued)

CONTROLSS-ePWM: An ePWM Glitch can Occur if a Trip Remains Active at the End of the Blanking Window



Workaround(s): Extend or reduce the blanking window to avoid any undesired trip action.

i2358 CONTROLSS-ePWM: Trip Events Will Not be Filtered by the Blanking Window for

the First 3 Cycles After the Start of a Blanking

Details: The Blanking Window will not blank trip events for the first 3 cycles after the start of a

Blanking Window. DCEVTFILT may continue to reflect changes in the DCxEVTy signals. If DCEVTFILT is enabled, this may impact subsequent subsystems that are configured (for example, the Trip Zone submodule, TZ interrupts, ADC SOC, or the PWM output).

Workaround(s): Start the Blanking Window 3 cycles before blanking is required. If a Blanking Window is

needed at a period boundary, start the Blanking Window 3 cycles before the beginning of the next period. This works because Blanking Windows persist across period boundaries.

i2359 CONTROLSS-CMPSS:Prescaler counter behaviour different from spec when

DACSOURCE is made 0 or reconfigured as 1

Details: While the prescaler is running if we make DACSOURCE = 0 the prescale counter will not

reset and and if the enable condition is LOW the value stays and when the DACSOURCE is again configured as 1 the counter starts from the previous value which was retained. This bug is present only when DACSOURCE is configured during the prescale counter

running.

Workaround(s): Issue a soft reset between DACSOURCE configuration which is not a dynamic

configuration.



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

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•	Added Advisory i2348; VDDA1V8 Static Power leakage
•	Added Advisory i2329: MDIO: MDIO interface corruption (CPSW and PRU-ICSS)4
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